

This declaration of conformity is issued under the sole responsibility of the manufacturer.

Manufacturer's Name: N-TRON Corporation  
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QUALITY MANAGEMENT SYSTEM  
CERTIFIED BY DNV  
**ISO 9001:2008**

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Hereby, N-TRON Corporation declares that these industrial Ethernet devices are in compliance with the essential requirements and other relevant provisions of Directives 1999/5/EC and 2004/108/EC.

Listing of conforming devices:

104TX	4 port 10/100BaseTX Industrial Ethernet Switch, DIN-Rail
105TX	5 port 10/100BaseTX Industrial Ethernet Switch, DIN-Rail Input Voltage 10-30 VDC; Operating Temperature -40° to 80°C
105TX-SL	5 port 10/100BaseTX Industrial Ethernet Switch, DIN-Rail, Slimline Design; Operating Temperature -40° to 85°C

Standards of conformance: This product herewith complies with the requirements of standards presented below.

US Federal Communications  
Commission  
Industry Canada



- ANSI C63.4-2003: Method of Measurements of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the 9kHz to 40GHz
- US Code of Federal Regulations (CFR): Title 47, Part 15, Radio Frequency Devices, Subpart B, Unintentional Radiators (October 2009)
- Industry Canada ICES-003 Issue 3: Digital Apparatus (November 2004)

European Union  
Conformité  
Européenne



- 2004/108/EEC – Electromagnetic Compatibility (EMC) Directive
- EN 55011:1998+A1:1999+A2:2002 – Industrial, Scientific and Medical (ISM) Radio-Frequency Equipment – Radio Disturbance Characteristics
- IEC 61000-4-2 Ed. 1.2 – Electrostatic Discharge Immunity Test
- IEC 61000-4-3 Ed. 2.1 – Radiated, Radio-Frequency, Electromagnetic Field Immunity Test
- IEC 61000-4-4 2nd Ed. – Electrical Fast Transient/Burst Immunity Test
- IEC 61000-4-5 2nd Ed. – Surge Immunity Test
- IEC 61000-4-6 Ed. 2.1 – Immunity to Conducted Disturbances Induced by Radio-Frequency Fields

Mr. Jerry Simmons  
Regulatory Manager

NVLAP Lab. Accredited to ISO/IEC 17025:2005  
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Test Report: 10-0252.C01.24/C08.14